Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10632823	VENKATACHALAM, VIDYA
Examiner	Art Unit
Bloom, Nathan	2609

	SEAR	CHED	
Class	Subclass	Date	Examiner
382	150,155-161		

SEARCH NOTES				
Search Notes	Date	Examiner		
Inventor and Assignee Search	2/06/07			
East Keyword Search	2/08/07			
IEEE Search: Inspection Systems using a Hough or Radon transform and Neural Networks	2/13/2007			
ACM and SPIE Search: Inspection systems using a Hough or Radon transform and Neural Networks	2/14/2007			
Consulted Samir Ahmed	2/15/2007			
Consulted Tommy Chin regarding 101 rejection	2/15/2007			

	INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner	

U.S. Patent and Trademark Office Part of Paper No.: